

L Number	Hits	Search Text	DB	Time stamp
2	6515	memor\$ and cell\$2 and replac\$ and address\$ and writ\$4 and read\$4 and test\$5 and compari\$ and activ\$	USPAT; US-PGPUB; EPO; JPO	2003/09/25 10:00
3	201	memor\$ adj cell\$2 adj replac\$ and address\$ and writ\$4 and read\$4 and test\$5 and compari\$ and activ\$	USPAT; US-PGPUB; EPO; JPO	2003/09/25 10:13
4	167	memor\$ adj cell\$2 adj replac\$ and address\$ and writ\$4 and read\$4 and test\$5 and compari\$ and activ\$ and fus\$5	USPAT; US-PGPUB; EPO; JPO	2003/09/25 10:14

	U	1	Document ID	Issue Date	Pages	Title	Current OR
1	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	US 5983358 A	19991109	23	Semiconductor memory having redundancy circuit	714/6
2	<input type="checkbox"/>	<input checked="" type="checkbox"/>	US 5822257 A	19981013	51	Semiconductor memory device capable of relieving fixed-failure memory cells and refresh-failure memory cells	365/200
3	<input type="checkbox"/>	<input checked="" type="checkbox"/>	US 5764576 A	19980609	50	Semiconductor memory device and method of checking same for defect	365/200
4	<input type="checkbox"/>	<input checked="" type="checkbox"/>	US 5703817 A	19971230	22	Semiconductor memory device	365/200
5	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	US 5689465 A	19971118	36	Semiconductor memory device and defective memory cell correction circuit	365/200
6	<input type="checkbox"/>	<input checked="" type="checkbox"/>	US 5666314 A	19970909	109	Semiconductor memory device for selecting and deselecting blocks of word lines	365/200
7	<input type="checkbox"/>	<input checked="" type="checkbox"/>	US 5661689 A	19970826	9	Semiconductor device incorporating fuse-type roll call circuit	365/200
8	<input type="checkbox"/>	<input checked="" type="checkbox"/>	US 5659517 A	19970819	45	Semiconductor memory device with an improved hierarchical power supply line configuration	365/226
9	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	US 5550394 A	19960827	37	Semiconductor memory device and defective memory cell correction circuit	257/209
10	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	US 5506499 A	19960409	16	Multiple probing of an auxiliary test pad which allows for reliable bonding to a primary bonding pad	324/158.1

	Current XRef	Retrieval Classif	Inventor	S	C	P	2	3	4	5	Image Doc. Displayed	PT
1			Horiguchi, Masashi et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 5983358	<input type="checkbox"/>
2	365/189.02; 365/189.05; 365/189.07; 365/189.08; 365/222; 365/225.7; 365/227; 365/228; 365/230.03		Ogawa, Junji	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 5822257	<input type="checkbox"/>
3	365/201; 365/230.06		Hidaka, Hideto et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 5764576	<input type="checkbox"/>
4	365/225.7; 714/710; 714/711		Shiratake, Shinichiro et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 5703817	<input type="checkbox"/>
5	365/225.7; 365/230.03; 714/710		Sukegawa, Shunichi et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 5689465	<input type="checkbox"/>
6	365/230.03; 365/230.06		Akaogi, Takao et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 5666314	<input type="checkbox"/>
7	365/201; 365/225.7		Shinkai, Eiji	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 5661689	<input type="checkbox"/>
8	365/228		Arimoto, Kazutami et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 5659517	<input type="checkbox"/>
9	257/529; 365/200; 714/710		Sukegawa, Shunichi et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 5550394	<input type="checkbox"/>
10	29/847		Puar, Deepraj S.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 5506499	<input type="checkbox"/>

	U	1	Document ID	Issue Date	Pages	Title	Current OR
11	<input type="checkbox"/>	<input checked="" type="checkbox"/>	US 5471427 A	199511128	27	Circuit for repairing defective bit in semiconductor memory device and repairing method	365/200
12	<input type="checkbox"/>	<input checked="" type="checkbox"/>	US 5452251 A	19950919	110	Semiconductor memory device for selecting and deselecting blocks of word lines	365/200
13	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	US 5422850 A	19950606	26	Semiconductor memory device and defective memory cell repair circuit	365/200
14	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	US 5379258 A	19950103	32	Circuit for repairing defective bit in semiconductor memory device and repairing method	365/200
15	<input checked="" type="checkbox"/>	<input checked="" type="checkbox"/>	US 5293386 A	19940308	50	Integrated semiconductor memory with parallel test capability and redundancy method	714/718
16	<input type="checkbox"/>	<input checked="" type="checkbox"/>	US 5179536 A	19930112	57	Semiconductor memory device having means for replacing defective memory cells	365/200

	Current xRef	Retrieval Classif	Inventor	S	C	P	2	3	4	5	Image Doc. Displayed	PT
11	365/225.7		Murakami, Shuji et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 5471427	<input type="checkbox"/>
12	365/185.13; 365/218; 365/230.03		Akaogi, Takao et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 5452251	<input type="checkbox"/>
13	326/13; 327/526; 365/225.7; 365/230.02; 365/230.06		Sukegawa, Shunichi et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 5422850	<input type="checkbox"/>
14	714/711		Murakami, Shuji et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 5379258	<input type="checkbox"/>
15	365/201; 714/711		Muhmenthaler, Peter et al.	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 5293386	<input type="checkbox"/>
16	365/185.04; 714/710		Kasa, Yasushi et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	US 5179536	<input type="checkbox"/>